

## CLAIM AMENDMENTS

Please amend claims 1, 9, and 18 as follows.

1. (Currently Amended) A timing circuit comprising:

at least one driving circuit outputting an output signal onto [an] a first  
interconnect;

at least one receiving circuit receiving an input signal from [an] a second  
interconnect;

a phase locked loop receiving a reference clock signal and a delayed  
feedback clock signal, and supplying an output clock signal to said at least one driving  
circuit and said at least one receiving circuit, said phase locked loop generating said  
output clock signal according to said received reference clock signal and delayed  
feedback clock signal; and

first and second delay elements located in the path of said reference clock  
signal and the path of a feedback clock signal, respectively, said first and second delay  
elements being configured to provide a delay in order to make said output signal meet a  
predetermined valid data timing requirement, an individual delay element comprising:

at least one delay buffer to receive said reference clock and to generate a  
delayed reference clock, said reference clock having a falling edge, said delayed reference clock  
having a rising edge;

a phase detector to determine whether said rising edge of said delayed  
reference clock is early or late with respect to said falling edge of said reference clock;

a counter to increment if said rising edge of said delayed reference clock is  
early with respect to said falling edge of the reference clock and to decrement if said rising edge  
of said delayed reference clock is late with respect to said falling edge of said reference clock;  
and

a digital-to-analog converter (DAC) coupled to receive an output from  
said counter, said DAC further to increase a bias applied to said delay buffer is if said rising edge  
of said delayed reference clock is early with respect to said falling edge of said reference clock.

2. (Original) A timing circuit as claimed in claim 1, wherein delay elements are located only in the reference clock and feedback clock paths.
3. (Original) A timing circuit as claimed in claim 1, wherein said first and second delay elements are self-calibrating delay cells.
4. (Original) A timing circuit connection as claimed in claim 3, wherein said self-calibrating delay cells calibrate themselves to meet specified timing adjustment, granularity and/or range.
5. (Previously Presented) A timing circuit as claimed in claim 4, wherein said self-calibrating delay cells use a digital compensation technique to reduce process, voltage, and/or temperature (PVT) variations.
6. (Original) A timing circuit as claimed in claim 5, wherein said digital compensation technique utilizes a multi-tap delay buffer in the feedback clock signal path to delay the feedback clock signal, the amount of delay being controlled by selecting a tap of said multi-tap delay buffer.
7. (Original) A timing circuit as claimed in claim 1, wherein said at least one driving circuit comprises a plurality of driving circuits and said phase locked loop provides said output clock signal to all of said plurality of driving circuits.
8. (Previously Presented) A timing circuit as claimed in claim 7, wherein said plurality of driving circuits drive respective output signals from an integrated circuit (IC) chip.
9. (Currently Amended) An I/O circuit comprising:
  - a transmitting device outputting at least one output signal, said transmitting device having:
    - at least one driving circuit, the number of driving circuits corresponding to the number of output signals;

a phase locked loop receiving a reference clock signal and a delayed feedback clock signal, said phase locked loop generating said output clock signal according to said received reference clock signal and delayed feedback clock signal;

first and second delay elements located in the path of said reference clock signal and the path of a feedback clock signal, respectively, an individual delay element comprising:

at least one delay buffer to receive said reference clock and to generate a delayed reference clock, said reference clock having a falling edge, said delayed reference clock having a rising edge;

a phase detector to determine whether said rising edge of said delayed reference clock is early or late with respect to said falling edge of said reference clock;

a counter to increment if said rising edge of said delayed reference clock is early with respect to said falling edge of the reference clock and to decrement if said rising edge of said delayed reference clock is late with respect to said falling edge of said reference clock;  
and

a digital-to-analog converter (DAC) coupled to receive an output from said counter, said DAC further to increase a bias applied to said delay buffer if said rising edge of said delayed reference clock is early with respect to said falling edge of said reference clock  
~~said second delay element to delay the feedback clock signal, to determine whether a rising edge of the delayed feedback clock signal is early or late with respect to a falling edge of the feedback clock signal, and to increase or decrease the delay of the feedback clock signal based on whether the rising edge of the delayed feedback clock signal is early or late with respect to the falling edge of the feedback clock signal; and~~

a receiving device having at least one receiving circuit receiving said at least one output signal from said transmitting device and an input signal from an interconnect, said phase locked loop supplying an output clock signal to said at least one driving circuit and said at least one receiving circuit, the timing of said received output signal or at least one output signal meeting said predetermined valid timing requirement.

10. (Original) An I/O circuit as claimed in claim 9, wherein delay elements are located only in the reference clock and feedback clock paths.

11. (Original) An I/O circuit as claimed in claim 9, wherein said first and second delay elements are self-calibrating delay cells.

12. (Original) An I/O circuit as claimed in claim 11, wherein said self-calibrating delay cells calibrate themselves to meet specified timing adjustment, granularity and/or range.

13. (Previously Presented) An I/O circuit as claimed in claim 12, wherein said self-calibrating delay cells use a digital compensation technique to reduce process, voltage, and/or temperature (PVT) variations.

14. (Original) An I/O circuit as claimed in claim 13, wherein said digital compensation technique utilizes a multi-tap delay buffer in the feedback clock signal path to delay the feedback clock signal, the amount of delay being controlled by selecting a tap of said multi-tap delay buffer.

15. (Original) An I/O circuit as claimed in claim 9, wherein said at least one driving circuit comprises a plurality of driving circuits and said phase locked loop provides said output clock signal to all of said plurality of driving circuits.

16. (Previously Presented) An I/O circuit as claimed in claim 9, wherein said transmitting device and said receiving device comprise IC chips and said output signals are driven on a bus between said integrated circuit (IC) chips.

17. (Original) An I/O circuit as claimed in claim 16, wherein said transmitting device and said receiving device are mounted at a distance from each other on a printed circuit board.

18. (Currently Amended) A method of transferring a signal from a transmitting device to a receiving device comprising:

outputting said signal from said transmitting device using a driving circuit;

receiving a reference clock signal in said transmitting device;

generating an output clock signal according to said received reference clock signal and a delayed feedback clock signal in a phase locked loop;

supplying the output clock signal to said at least one driving circuit and at least one receiving circuit; and

providing a delay in a path of said reference clock signal and a path of said feedback clock signal to make said at least one output signal meet a predetermined valid data timing requirement by:

receiving said reference clock at a delay element, said reference clock having a falling edge;

generating a delayed reference clock, said delayed reference clock having a rising edge;

determining whether said rising edge of said delayed reference clock is early or late with respect to said falling edge of said reference clock;

incrementing a counter if said rising edge of said delayed reference clock is early with respect to said falling edge of said reference clock;

decrementing said counter if said rising edge of said delayed reference clock is late with respect to said falling edge of said reference clock; and

increasing a bias applied to said delay element is if said rising edge of said delayed reference clock is early with respect to said falling edge of said reference clock.

19. (Original) The method recited in claim 18, wherein said delay is provided by self-calibrating delay cells which calibrate themselves to meet specified timing adjustment, granularity and/or range.

20. (Previously Presented) The method recited in claim 19, wherein said self-calibrating delay cells use a digital compensation technique to reduce process, voltage, and/or temperature (PVT) variations.

21. (Canceled)